

Notice of References Cited	Application/Control No. 09/995,696		Applicant(s)/Patent Under Reexamination WAKABAYASHI, TAKEFUMI	
	Examiner SARGON N. NANO		Art Unit 2157	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0051168	05-2002	Yashiki, Satoshi	358/1.15
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FOREIGN PATENT DOCUMENTS

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